

RF Exposure Evaluation

According to KDB 447498 D01 General RF Exposure Guidance v06 and part 2.1093, Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Test Exclusion Threshold condition(s), listed below, is (are) satisfied.

For 100 MHz to 6 GHz and test separation distances ≤ 50 mm, the 1-g and 10-g SAR test exclusion thresholds are determined by the following:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0$ for 1-g SAR, and ≤ 7.5 for 10-g extremity SAR, where

$f(\text{GHz})$ is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation

The result is rounded to one decimal place for comparison

Here,

The device has been evaluated to meet general RF exposure requirement. The device can be used in portable exposure condition without restriction.

For EDR

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	1g SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	7.12	5.152	7±1	8	6.310	<5	1.95576	3.00	YES
	2.441	6.96	4.966	7±1	8	6.310	<5	1.97158	3.00	YES
	2.480	6.32	4.285	7±1	8	6.310	<5	1.98727	3.00	YES
$\pi/4$ -DQPSK	2.402	7.04	5.058	7±1	8	6.310	<5	1.95576	3.00	YES
	2.441	7.26	5.321	7±1	8	6.310	<5	1.97158	3.00	YES
	2.480	6.53	4.498	7±1	8	6.310	<5	1.98727	3.00	YES
8DPSK	2.402	7.58	5.728	7±1	8	6.310	<5	1.95576	3.00	YES
	2.441	7.48	5.598	7±1	8	6.310	<5	1.97158	3.00	YES
	2.480	6.84	4.831	7±1	8	6.310	<5	1.98727	3.00	YES

Conclusion:

For the max result : $1.98727 \leq 3.0$ for 1-g SAR, No SAR is required.

So a SAR test is not required

Signature:



Date: 2026-06-11

NAME AND TITLE (Please print or type): Jason Chen /Manager

COMPANY (Please print or type): Shenzhen ATA Testing Lab. Inc./ 4th Floor, Building 10,No.60 Nanchang Road,Nanchang Community, Xixiang Street, Bao'an District,Shenzhen City, China